PCN Number:	20180809002.1**.A**	**PCN Date:**	Nov 13, 2018
Title:	Transfer of select C10 devices from ANAM-1 to DMOS5 Wafer Fab site		
Customer Contact:	PCN Manager	**Dept:**	Quality Services
Proposed 1st Ship Date:	Nov 13, 2018	**Estimated Sample Availability:**	Date provided at sample request.

Change Type:		
☐ Assembly Site	☐ Assembly Process	☐ Assembly Materials
☐ Design	☐ Electrical Specification	☐ Mechanical Specification
☐ Test Site	☐ Packing/Shipping/Labeling	☐ Test Process
☒ Wafer Bump Site	☐ Wafer Bump Material	☐ Wafer Bump Process
☒ Wafer Fab Site	☐ Wafer Fab Materials	☐ Wafer Fab Process
	☐ Part number change	

PCN Details

Description of Change:

Revision A is to announce the addition of new devices that were not included on the original PCN notification. These new devices are highlighted and **bolded** in the device list below. The expected first shipment date for these new devices will be 90 days from this notice **(February 12, 2019)** for these newly added devices only. The proposed 1st ship date of Nov 13, 2018 still applies for the original set of devices.

This change notification is to announce the transfer of select devices from ANAM-1 to the DMOS5 Wafer Fab site. Fab support from ANAM-1 has been discontinued. Buffer inventory has been built to cover the notification period of this change notification.

Current (Discontinued)				**New (Transfer to Location)**			
Current Fab Site	**Fab Process**	**Probe Site**	**Wafer Diameter**	**New Fab Site**	**Fab Process**	**Probe Site**	**Wafer Diameter**
ANAM-1	C10	DBUMP	200mm	DMOS5	C10	EBT	200mm

Reason for Change:

Discontinued Fab support from ANAM-1

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Current:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
ANAM-1	ANM	KOR	Bucheon-si

New:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
DP1DM5	**DM5**	**USA**	**Dallas**

Sample product shipping label (not actual product label)

Product Affected:

TLK1211RCP	**TLK1221RHATG4**	TLK1501IRCPR	TLK2501IRCPG4
TLK1221RHAR	TLK1501IRCP	TLK1501IRCPRG4	TLK2501IRCPR
TLK1221RHARG4	TLK1501IRCPG4	TLK2501IRCP	TLK2501IRCPRG4
TLK1221RHAT			

Qualification Report

Approve Date 24-July-2018

Qualification Results
Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: TLK1501IRCP	QBS Process Reference: TLK2500IRCP	QBS Package Reference: TLK2201BIRCP
AC	Autoclave 121C, 2atm	96 Hours	-	3/231/0	3/231/0
CDM	ESD - CDM	1000 V	1/3/0	-	-
ED	Electrical Characterization	Per Data Sheet Parameters	Pass	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	-
HBM	ESD - HBM	4000 V	1/3/0	-	-
HTOL	Life Test, 155C	240 Hours	-	3/231/0	-
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	3/135/0	3/135/0
LU	Latch-up	(Per JESD78)	1/6/0	-	-
T/C	Temp Cycle -65C/150C	500 Cycles	-	-	3/231/0

- QBS: Qual By Similarity
- Qual Device TLK1501IRCP is qualified at LEVEL3-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:
Qualified Pb-Free(SMT) and Green

Qualification Report

Approve Date 24-July-2018

Qualification Results
Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: TLK2501IRCP	QBS Process Reference: TLK2500IRCP	QBS Package Reference: TLK2201BIRCP
AC	Autoclave 121C, 2atm	96 Hours	-	3/231/0	3/231/0
CDM	ESD - CDM	1000 V	1/3/0	-	-
ED	Electrical Characterization	Per Data Sheet Parameters	Pass	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	-
HBM	ESD - HBM	4000 V	1/3/0	-	-
HTOL	Life Test, 155C	240 Hours	-	3/231/0	-
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	3/135/0	3/135/0
LU	Latch-up	(Per JESD78)	1/6/0	-	-
T/C	Temp Cycle -65C/150C	500 Cycles	-	-	3/231/0

- QBS: Qual By Similarity
- Qual Device TLK2501IRCP is qualified at LEVEL3-260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k hours, 140C/480 hours, 150C/300 hours, 155C/240 hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k hours, and 170C/420 hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:
Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com